

**Search Notes**

Application/Control No.

10/594,202

Examiner

John Kreck

Applicant(s)/Patent under  
Reexamination

CHAN ET AL.

Art Unit

3672

**SEARCHED**

Class	Subclass	Date	Examiner
588	256,252, 315, 412	6/4/2010	JK

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
text	6/4/2010	JK